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Title: Infrared radiation measurement system for infrared imaging system, has n-type metal-oxide-semiconductor measurement transistor with gate connected to output operational amplifier, where output is connected to gate reference transistor

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Abstract: NOVELTY - The system has an n-type metal-oxide-semiconductor (N-MOS) reference transistor (242^{*}) with a source connected to an end a reference mirror branch (236^{*}). An operational amplifier (240) has a negative input connected to the source and an output connected to a gate the transistor. An N-MOS measurement transistor (242) has a gate connected to the output the amplifier. A measurement unit measures difference between measurement current (i_{mes1}) passing via a measurement bolometer (222) e.g. infrared bolometer, and current (i_{ref}) passing via a measurement mirror branch (236).

USE - Infrared radiation measurement system for use in an imaging system (claimed) i.e. infrared imaging system. Can also be used for a terahertz imaging system.

ADVANTAGE - The design the measurement system eliminates the need to have transistors in a current mirror assembly, thus avoiding problems resulting from potential a drain a polarization transistor a reference bolometer and load mirror transistors, and hence enabling the imaging system to be compatible with the current tendency reduction supply voltage.

DESCRIPTION DRAWING(S) - The drawing shows a circuit diagram a part a row cells in an infrared imaging system.

Measurement current (i_{mes1})

Current passing via measurement mirror branch (i_{ref})

Measurement bolometer (222)

Measurement mirror branch (236)

Reference mirror branch (236^{*})

Operational amplifier (240)

N-MOS measurement transistor (242)

N-MOS reference transistor (242^{*})

Drawing:

Derwent Class Code(s): S03 (Scientific Instrumentation, photometry, calorimetry)

Derwent Manual Code(s): S03-A03

IPC: G01J-005/22; G01R-029/08; G01J-005/20; H01L-027/146

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